

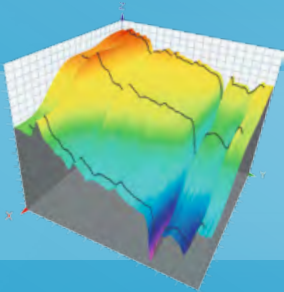


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R&D Geometry Tool > Picture 1
- ((**MX 704**
R&D Tool for measuring Thickness, Resistivity, Bow, Waviness, Saw Marks and P/N > Picture 2

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